

Session 1.2 Nanofabrication

Time: Wednesday, 06.09.2023

Location: Humboldtbaue, Lecture Room HU-211/212

Chairman: T. Kissinger (D-Ilmenau)

9:00 a.m.	T. Busani, I. Stricklin (US-New Mexico), I. Rangelow (D-Ilmenau)
Multifunction probes approach to integrate atomic metrology with analog/digital lithography and near field spectroscopy	
9:20 a.m.	T. Ma, M. Fahrbach, J. Xu, M. Vergin, A. Waag, E. Peiner (D-Braunschweig)
Imaging the mechanical properties of nanowire arrays	
9:40 a.m.	J. Stauffenberg, J. Belkner, J. Ruprecht, I. Ortlepp, E. Manske (D-Ilmenau)
Tip-based nanofabrication and nanometrology in combination with a planar nanopositioning machine (NFM-100)	
10:00 a.m.	A.S. Huaman, J. Reger (D-Ilmenau)
Robust adaptive tracking control for highly dynamic nanoprecision motion Systems	
10:20 - 10:40 a.m. Coffee break and Visits of Expositions	
10:40 a.m.	R. Knechtel (D-Schmalkalden), U. Schwarz (D-Erfurt)
Wafer bonding technologies for nano-, micro- and macro-system realization and integration	
11:00 a.m.	K. Lauer, C. Möller, S. Reiß, E. Hiller, T. Ortlepp (D-Erfurt), A. Flötotto, K. Peh, D. Bratek, R. Müller, D. Schulze, S. Krischok, W. Beenken, E. Runge (D- Ilmenau)
Defect-engineering for better silicon devices based on understanding of the As _i -Si _i -defect	

11:20 a.m.	H. Nguyen, G. Apte, M. Soter, D. Madkatte (D-Heiligenstadt)
Mask-free nanoimprinting using fluid force microscopy for platelet storage application	
11:40 a.m.	M. Rodenberg, L.J. Munker, R. Tutsch, P.J. Walla, T. Weimann (D-Braunschweig)
Using photo-activated localization microscopy (PALM) for imaging fluorophore-doped photoresists	
12:00 noon – 1:00 p.m. Lunch and Visits of Expositions	

